STAr Technologies Announces Hybrid Automatic Test Equipment (ATE) for Parametric, Reliability and KGD Tests of 3D ICs

Hsinchu, Taiwan, R.O.C., Feb. 18, 2015 - STAr Technologies, a leading supplier of semiconductor test systems and probe cards, is pleased to announce its new STAr Gemini Automatic Test Equipment (ATE) for 3D IC tests. STAr Gemini is one of the first hybrid ATE systems with extensive test capabilities encompassing parametric, reliability and Known Good Die (KGD) tests of 3D ICs.

STAr Gemini's test capabilities include; process control monitoring and performance qualification of Through Silicon Via (TSV), Silicon Interposer, Copper Pillar Micro-Bumps, and Known Good Die functional tests of stacked dies. STAr Gemini's specification presents an extension to the known ATE systems in the industry by featuring an innovative architecture to address customers' needs with lowest cost-of-test while reducing time-to-market of qualified 3D ICs.

Features include:

- 20 instrument module slots and extensions for integrating external instruments
- Up to 960 channels of precision DC Vis
- 96 channels DIO modules for functional tests
- Precision tests for pico-A currents, milli-V voltages, micro-Ω resistance, and femto-F capacitances
- Multiplexed per-pin low-leakage switch matrix

"STAr Gemini is designed based on customer needs," stated Dr. Choon-Leogn Lou, CEO of STAr Technologies. "The system is a breakthrough in the industry with multiple capabilities spanning across parametric, reliability and functional tests. This combination provides customers the ability to tighten manufacturing process variations, improve yield and product reliability. This will definitely become an indispensable ATE for qualification of 3D ICs."

About STAr Technologies

STAr Technologies is a leading test solutions provider in the semiconductor industry today. Specializing in automated test equipment, test instruments, tests software, probe cards, test sockets and technical services, our expertise covers parametric electrical test (E-test), wafer-level and package-level reliability (WLR & PLR), mixed signal automatic test equipment (ATE), parametric/wafer sort probe cards, load boards and other consumables. STAr Technologies’
headquarter is based in Hsinchu, Taiwan with subsidiaries in U.S.A., Japan, South Korea, Singapore, China and India.

To learn more about STAr Technologies please visit www.star-quest.com.